

NEBU NFC Devices Development FI
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Product information:

RM-216

FCCID: PYARM-216V

IC: 661V-RM216V

The test lab confirms that loop antenna was used in RFID radiated measurements below 30MHz, (Report Cph_FCC_0642_04).
The lab will add a note of this in all future reports

Place of Issue: Helsinki, Finland

Date of Issue: 30 Jan. 2007

Test Manager:

Signature: _____



Name: Vesa Vuorio